

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT Form PTO-1449 (Modified) Use several sheets if necessary				COMPLETE IF KNOWN	
				Application Number	10/687,111
				Confirmation Number	7235
				Filing Date	October 15, 2003
				First Named Inventor	Trung T. Doan
				Group Art Unit	2881
Examiner Name	Jack I. Berman				
Attorney Docket No.	108298731US				
Sheet	1	of	2		

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EXAMINER <i>Jack Berman</i>	DATE CONSIDERED <i>5/27/2005</i>
*EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application(s).	

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